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Please send me information on the following Tencor products:

General

- ☐ Corporate brochure
- ☐ 1995 Annual Report

Wafer Inspection Division

- ☐ Surfscan AIT In-Line Defect Inspection System for Patterned Wafers
- ☐ Surfscan 7000 Series In-Line Contamination Monitoring System for Patterned Wafers
- ☐ Surfscan 6000 Series for Contamination Monitoring on Unpatterned Surfaces
- ☐ SwiftAccess Defect Data Management System
- ☐ Tencor CRS Laser-Confocal Defect Review Station

Film Measurement Division

- ☐ Prometrix Thin Film Product Overview
- ☐ Prometrix UV-1270SE / UV-1070 Thin Film Measurement Systems with Integrated SMIF Interface
- ☐ Prometrix UV-1250SE Thin Film Measurement System with Spectroscopic Ellipsometry

ASM Ex. 1022
IPR Petition - USP 7,808,396

- ☐ Prometrix UV-1050 Thin Film Measurement System with UV Spectrophotometry
- ☐ Prometrix FT-750 Film Thickness Measurement System
- ☐ SpectraMap Auto SM300 Film Thickness Mapping System
- ☐ OmniMap RS75/tc Sheet Resistance Mapping System
- ☐ OmniMap NC110 Non-Contact Metals Measurement System
- ☐ Resistivity At-A-Glance Overview

Metrology Division

Metrology Products for Fab Production

(Semiconductor and Thin Film Head):

- ☐ General Product Overview
- ☐ HRP-200 High-Resolution Profiler
- ☐ P-22 Automated Surface Profiler
- ☐ P-30 SMIF Profiler
- ☐ FLX-5400 Film Stress Measurement System

Metrology Products for Research and Development Applications:

- ☐ General Product Overview
- ☐ P-11 Long Scan Profiler
- ☐ P-10 Surface Profiler
- ☐ Alpha-Step 500 Surface Profiler
- ☐ FLX-2320 Film Stress Measurement System (to 500° C)
- ☐ FLX-2900 Film Stress Measurement System (to 900° C)

Metrology Products for the Flat Panel Display Industry:

- ☐ General Product Overview
- ☐ FP-20 Large Sample Surface Profiler
- ☐ P-11 Long Scan Profiler
- ☐ FLX-2350fp Flat Panel Film Stress Measurement System

Metrology Products for the Disk Industry:

- ☐ P-12 Disk Profiler

Metrology Products for Wafer Characterization:

- ☐ M-Gage 300 Metalization Monitor
- ☐ Sono-Gage 300 Resistivity, Thickness and Dopant Type Monitor

Technical Documentation

Please send me more information **about technical manuals on disk** for the following Tencor products:

- ☐ Wafer Surface Inspection and Data Analysis Systems
- ☐ Thin Film and Resistivity Measurement Systems
- ☐ Surface Profiling and Film Stress Measurement Systems

My need is:

- ☒ Immediate
- ☐ Next 6 months
- ☐ Information only

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